

Search Notes

Application/Control No.

10/617,029

Examiner

Hai C. Pham

Applicant(s)/Patent under
Reexamination

KOMIYA ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	240, 251- 252, 144	6/16/2005	HP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/16/2005	HP